Supplementary Information

Indium Turns Tellurium into Ovonic Threshold Switching Selector by Stabilizing Amorphous Network

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Figures

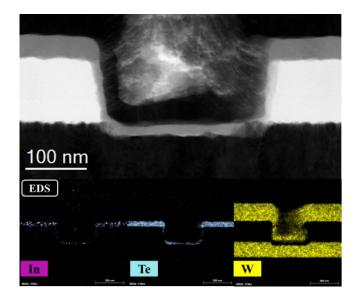


Fig. S1. Cross-sectional TEM image of the fabricated InTe₉ OTS device, with EDS mapping of In, Te, and W.

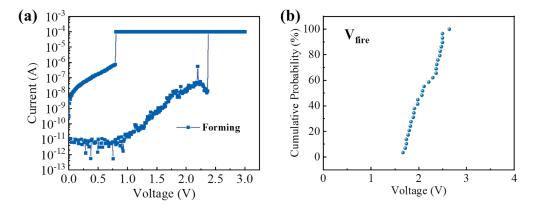


Fig. S2. (a) DC I-V sweep of the first-fire operation with a 100 μ A compliance current. (b) The distribution of the first-fire voltage (V_{ff}), centered around 2.2 V.

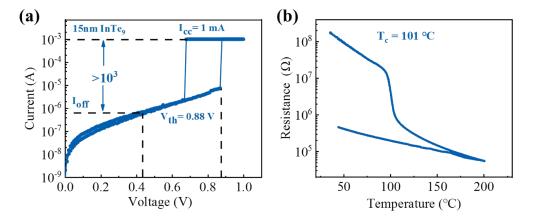


Fig. S3. (a) DC I-V sweep of the 15 nm-thick InTe₉ device, showing V_{th} and I_{off} of 0.88 V and 0.5 μ A, respectively. (b) The R-T relation of InTe₉ film, demonstrating that the crystallization temperature is ~100°C $_{\circ}$

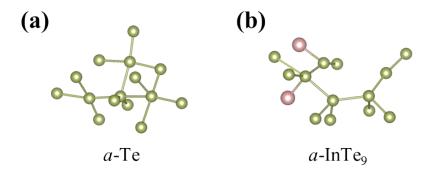


Fig. S4. MGS projected to the real space. (a-b) The over-coordinated Te atoms in a-Te and a-InTe₉, respectively.

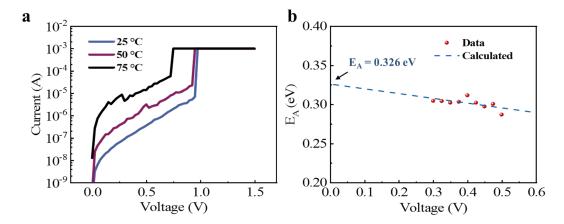


Fig. S5. (a) I-V-T measurement of OTS devices with a 1 mA compliance current. As the temperature increases, I_{off} and V_{th} decrease. (b) The voltage dependence of the activation energy for conduction (E_A).